

## STW45NM50FD

N-channel 500 V, 0.07 Ω, 45 A, TO-247 FDmesh™ Power MOSFET (with fast diode)

#### **Features**

Туре	V <sub>DSS</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
STW45NM50FD	500 V	< 0.1 Ω	45 A

- 100% avalanche tested
- High dv/dt and avalanche capabilities
- Low input capacitance and gate charge
- Low gate input resistance

#### **Application**

■ Switching applications

#### **Description**

The FDmesh™ associates all advantages of reduced on-resistance and fast switching with an intrinsic fast-recovery body diode. It is therefore strongly recommended for bridge topologies, in particular ZVS phase-shift converters.

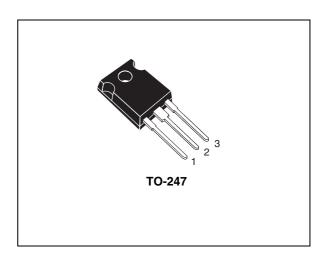


Figure 1. Internal schematic diagram

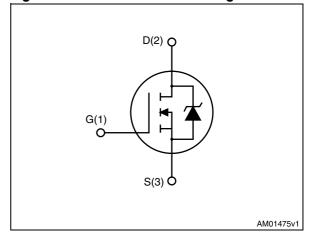


Table 1. Device summary

Order code	Marking	Package	Packaging
STW45NM50FD	W45NM50FD	TO-247	Tube

Contents STW45NM50FD

## **Contents**

1	Electrical ratings 3	}
2	Electrical characteristics 4	ļ
	2.1 Electrical characteristics (curves)6	3
3	Test circuits	}
4	Package mechanical data	)
5	Revision history	i

STW45NM50FD Electrical ratings

# 1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source voltage (V <sub>GS</sub> = 0)	500	V
V <sub>GS</sub>	Gate-source voltage	± 30	V
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 25 °C	45	Α
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> =100 °C	28.4	Α
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	180	Α
P <sub>TOT</sub>	Total dissipation at T <sub>C</sub> = 25 °C	417	W
	Derating factor	2.08	W/°C
dv/dt <sup>(2)</sup>	Peak diode recovery voltage slope	20	V/ns
T <sub>J</sub> T <sub>stg</sub>	Operating junction temperature Storage temperature	-65 to 150	°C

<sup>1.</sup> Pulse width limited by safe operating area

Table 3. Thermal resistance

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case max	0.3	°C/W
R <sub>thj-a</sub>	Thermal resistance junction-ambient max	30	°C/W
T <sub>I</sub>	Maximum lead temperature for soldering purpose	300	°C

Table 4. Avalanche data

Symbol	Parameter	Value	Unit
I <sub>AR</sub>	Avalanche current, repetitive or not-repetitive (pulse width limited by Tj max)	22.5	Α
E <sub>AS</sub>	Single pulse avalanche energy (starting $T_J = 25$ °C, $I_D = I_{AR}$ , $V_{DD} = 50$ V)	800	

<sup>2.</sup>  $I_{SD} \leq$  45 A, di/dt  $\leq$  400 A/ $\mu$ s,  $V_{DD}$  = 80% $V_{(BR)DSS}$ 

Electrical characteristics STW45NM50FD

### 2 Electrical characteristics

(T<sub>CASE</sub> = 25 °C unless otherwise specified)

Table 5. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	$I_D = 250 \ \mu\text{A}, \ V_{GS} = 0$	500			V
I <sub>DSS</sub>	Zero gate voltage drain current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = Max rating, V <sub>DS</sub> = Max rating @125 °C			10 100	μ <b>Α</b> μ <b>Α</b>
I <sub>GSS</sub>	Gate body leakage current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 30 V			±100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3	4	5	V
R <sub>DS(on)</sub>	Static drain-source on resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 22.5 A		0.07	0.10	Ω

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
9 <sub>fs</sub> <sup>(1)</sup>	Forward transconductance	$V_{DS} > I_{D(on)} \times R_{DS(on)max}$ $I_D = 22.5 \text{ A}$	-	20		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25 \text{ V, f} = 1 \text{ MHz, V}_{GS} = 0$	-	3600 1260 80		pF pF pF
C <sub>oss eq.</sub> <sup>(2)</sup>	Equivalent output capacitance	V <sub>GS</sub> =0, V <sub>DS</sub> =0 to 400 V	-	350		pF
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total gate charge Gate-source charge Gate-drain charge	$V_{DD}$ = 400 V, $I_{D}$ = 45 A $V_{GS}$ =10 V Figure 14	-	92 22 40	120	nC nC nC
R <sub>G</sub>	Gate input resistance	f=1 MHz Gate DC Bias= 0 test signal level = 20 mV open drain	-	2		Ω

<sup>1.</sup> Pulsed: pulse duration=300µs, duty cycle 1.5%

<sup>2.</sup>  $C_{oss\ eq}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ 

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub> t <sub>r</sub>	Turn-on delay time Rise time	$V_{DD}$ =250 V, $I_{D}$ = 22.5 A, $R_{G}$ =4.7 $\Omega$ , $V_{GS}$ =10 V Figure 15	-	26.5 107.5	-	ns ns
t <sub>r(Voff)</sub> t <sub>f</sub> t <sub>C</sub>	Off-voltage rise time Fall time Cross-over time	$V_{DD}$ =400 V, $I_{D}$ = 45 A, $R_{G}$ =4.7 $\Omega$ , $V_{GS}$ =10 V Figure 15	-	21.6 87.7 110.9	-	ns ns ns

Table 8. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		-		45	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		180	Α
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 45 A, V <sub>GS</sub> = 0	-		1.5	V
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 45 A, V <sub>DD</sub> = 100 V		200		ns
$Q_{rr}$	Reverse recovery charge	di/dt = 100 A/μs,	-	1600		nC
I <sub>RRM</sub>	Reverse recovery current	(see Figure 18)		16		Α
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 45 A, Tj = 150 °C		324		ns
$Q_{rr}$	Reverse recovery charge	di/dt = 100 A/μs,	-	4017		nC
I <sub>RRM</sub>	Reverse recovery current	V <sub>DD</sub> =100 V, (see Figure 18)		24.8		Α

<sup>1.</sup> Pulse width limited by safe operating area

<sup>2.</sup> Pulsed: pulse duration=300µs, duty cycle 1.5%

Electrical characteristics STW45NM50FD

#### 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

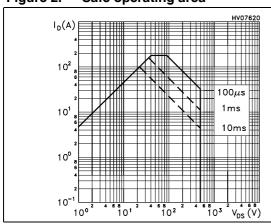


Figure 3. Thermal impedance

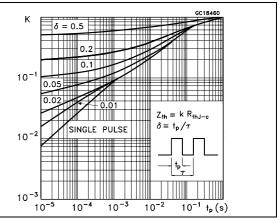


Figure 4. Output characteristics

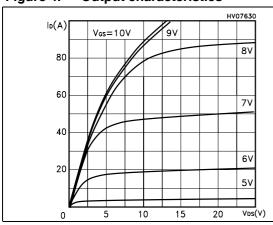


Figure 5. Transfer characteristics

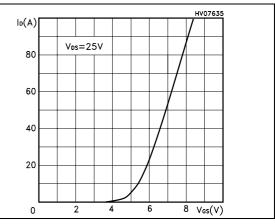


Figure 6. Transconductance

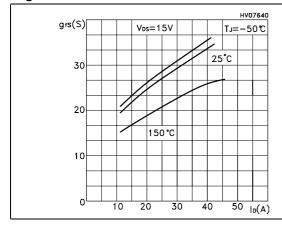
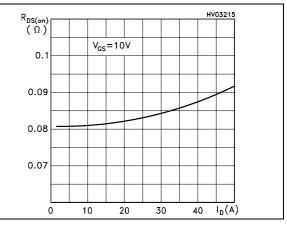


Figure 7. Static drain-source on resistance



HV07660  $V_{GS}(V)$ C(pF) f=1MHz Vgs=0V V<sub>DS</sub>=400V 12 12000 ID=45A 9 9000 6000 6 Ciss 3000 3 10 20 30 V<sub>DS</sub>(V) 40 60 80 100Qg(nC) 40 20

Figure 8. Gate charge vs gate-source voltage Figure 9. Capacitance variations

Figure 10. Normalized gate threshold voltage Figure 11. Normalized on resistance vs vs temperature temperature

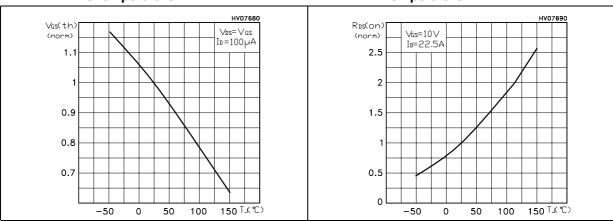
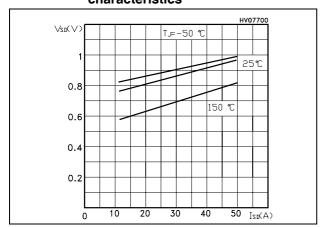


Figure 12. Source-drain diode forward characteristics



Test circuits STW45NM50FD

#### 3 Test circuits

Figure 13. Switching times test circuit for resistive load

Figure 14. Gate charge test circuit

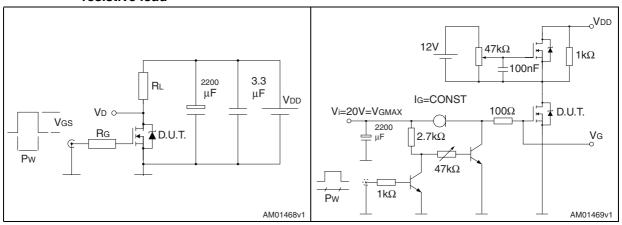


Figure 15. Test circuit for inductive load switching and diode recovery times

Figure 16. Unclamped inductive load test circuit

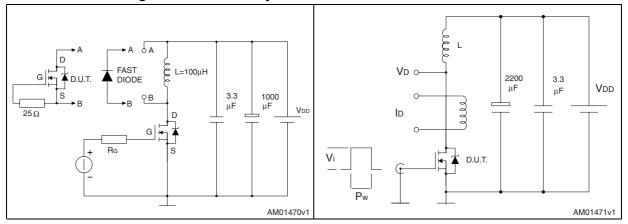
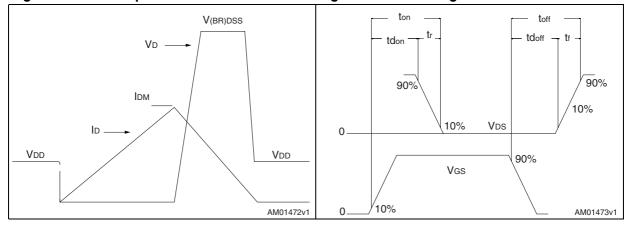


Figure 17. Unclamped inductive waveform

Figure 18. Switching time waveform

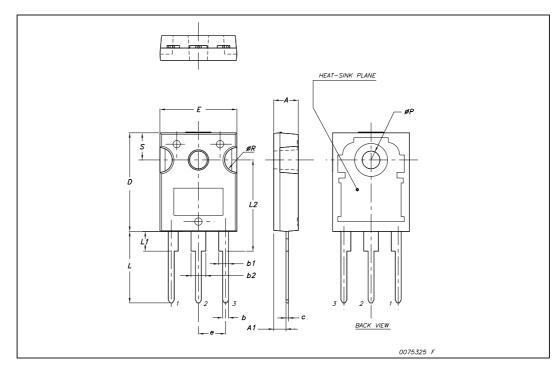


## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

TO-247 Mechanical data

Dim.		mm.	
Diiii.	Min.	Тур	Max.
Α	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
С	0.40		0.80
D	19.85		20.15
Е	15.45		15.75
е		5.45	
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
øΡ	3.55		3.65
øR	4.50		5.50
S		5.50	



STW45NM50FD Revision history

# 5 Revision history

Table 9. Document revision history

Date	Revision	Changes
05-Apr-2005	8	Modified value on Source drain diode
26-Apr-2006	9	New template
23-Jul-2009	10	Modified values on Switching times

#### Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

UNLESS EXPRESSLY APPROVED IN WRITING BY AN AUTHORIZED ST REPRESENTATIVE, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVE GRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER'S OWN RISK.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2009 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan -Malaysia - Malta - Morocco - Philippines - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com

12/12 Doc ID 7955 Rev 10

